

500V Super-junction Power MOSFET

Description

500V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The deep trench SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

Features

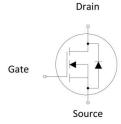
- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- Easy to use/drive
- RoHS compliant

Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Charger

TO-252







Device Marking and Package Information

Device	Package	Marking	
TPD50R3K8D	TO-252	50R3K8D	

Key Performance Parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	550	V
R _{DS(on),max}	3.8	Ω
$Q_{g,typ}$	2.8	nC
I _D	1	A
I _{D,pulse}	3	A
E _{OSS} @ 400V	0.24	μЈ



Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted					
Parameter			Symbol	Values	Unit
Continuous Drain Current	T _C = 25°C		l _D	1	Δ.
	T _C = 100°C			0.6	A
Pulsed Drain Current		(note1)	I _{D,pulse}	3	А
Gate-Source Voltage			V_{GSS}	±30V	V
Single Pulse Avalanche Energy (note2		(note2)	E _{AS}	5	mJ
Repetitive Avalanche Energy (note		(note2)	E _{AR}	0.01	mJ
Avalanche Current		I _{AR}	0.5	А	
Power Dissipation For TO-252			P_{D}	5.4	W
Continuous Diode Forward Current			I _S	1	А
Diode Pulsed Current		(note1)	I _{S,pulse}	3] ^
Operating Junction and Storage Temperature Range			T_J,T_stg	-55~+150	°C

Thermal Resistance For TO-252				
Parameter	Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	23	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	-0/00	



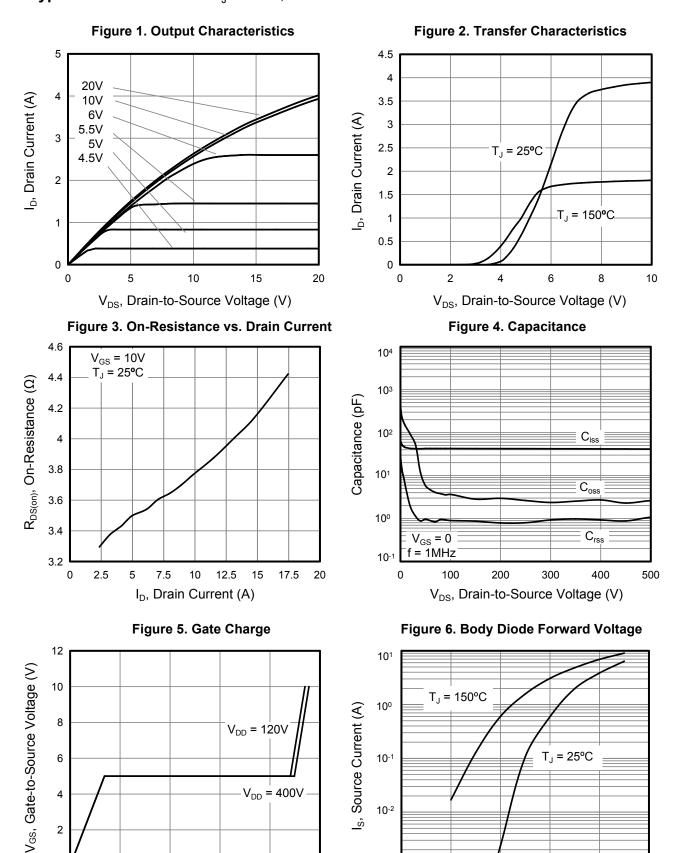
<u>.</u>			Value			
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	500			V
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 500V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μΑ
Gate-Source Leakage Current	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4	V
Drain-Source On-State-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 0.5A		3.5	3.8	Ω
Gate Resistance	R _G	f = 1.0MHz open drain		4.4		Ω
Dynamic Characteristics	-		-	-	_	
Input Capacitance	C _{iss}	\/ - 0\/		41		
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V$		3.6		pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		0.8		
Total Gate Charge	Q_g			2.8		
Gate-Source Charge	Q_{gs}	$V_{DD} = 400V$, $I_{D} = 1A$, $V_{GS} = 10V$		0.34		nC
Gate-Drain Charge	Q_{gd}	00		1.7		1
Turn-on Delay Time	t _{d(on)}			31.9		
Turn-on Rise Time	t _r	V _{DD} = 400V , I _D = 1A		8.6		
Turn-off Delay Time	$t_{d(off)}$	$R_G = 25\Omega$		39.6		ns
Turn-off Fall Time	t _f			52.9		
Drain-Source Body Diode Characte	ristics		•		•	
Body Diode Forward Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}$, $I_{SD} = \text{A}$, $V_{GS} = 0\text{V}$		0.9	1.2	V
Reverse Recovery Time	t _{rr}			35		ns
Reverse Recovery Charge	Q _{rr}	$V_R = 400V$, $I_F = I_S$, $di_F/dt = 100A/\mu s$		0.1		μC
Peak Reverse Recovery Current	I _{rrm}			1.4		Α

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. $I_D = 10A$, $V_{DD} = 50V$, $R_G = 25Ω$, Starting $T_J = 25$ °C
- 3. Identical low side and high side switch with identical $R_{\mbox{\scriptsize G}}$

0

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted



2.5

1.5

Q_q, Total Gate Charge (nC)

10-3

0.2

0.6

8.0

V_{SD}, Source-to-Drain Voltage (V)

Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted



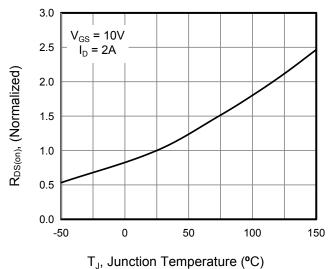


Figure 9. Transient Thermal Impedance For TO-252

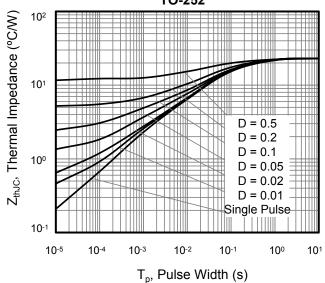


Figure 11. Typ. Coss Stored Energy

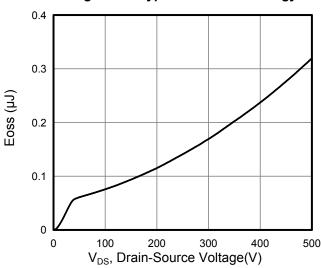
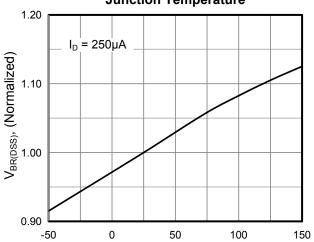
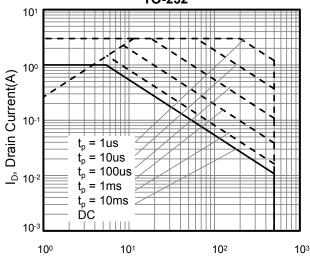


Figure 8. Breakdown Voltage vs. Junction Temperature



T_J, Junction Temperature (°C)

Figure 10. Safe Operation Area For TO-252



V_{DS}, Drain-Source Voltage(V)



Figure A: Gate Charge Test Circuit and Waveform

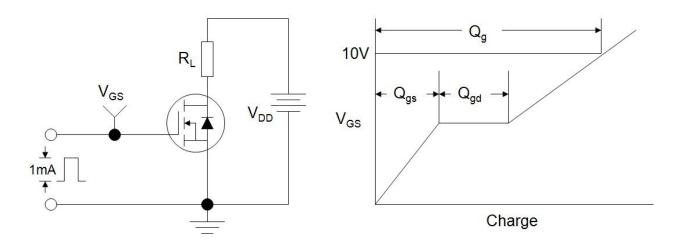


Figure B: Resistive Switching Test Circuit and Waveform

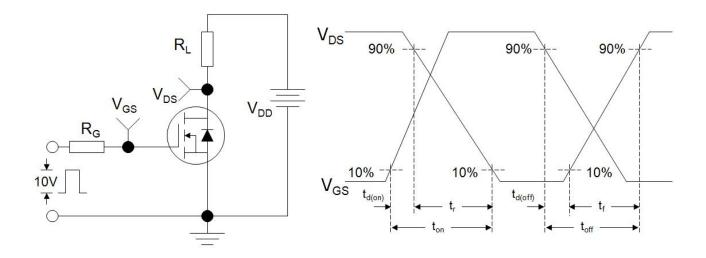
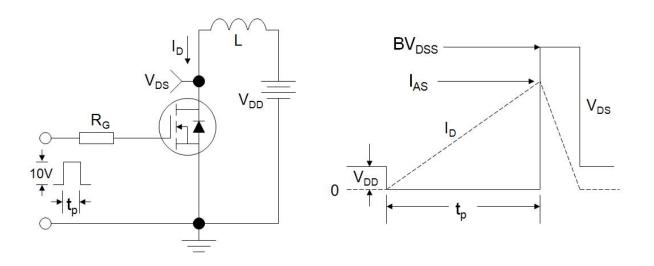
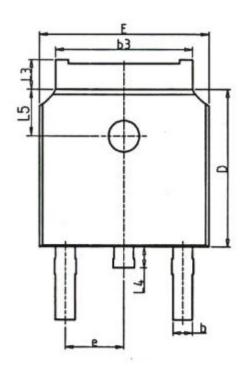


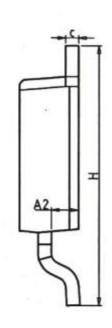
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

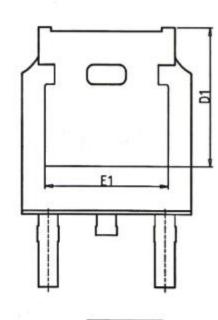


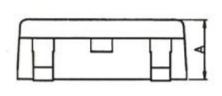


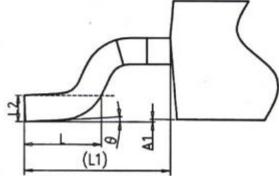
TO-252











Unit:mm				
Symbol	Min.	Nom	Max.	
Α	2.20	2.30	2.40	
A1	0.00	-	0.20	
A2	0.97	1.07	1.17	
b	0.68	0.78	0.90	
b3	5.20	5.33	5.50	
С	0.43	0.53	0.63	
D	5.98	6.10	6.22	
D1	5.30 REF			
E	6.40	6.60	6.80	
E1	4.63	-	-	

Unit:mm				
Symbol	Min.	Nom	Max.	
е		2.286 BSC		
Н	9.40	10.10	10.50	
L	1.38	1.50	1.75	
L1	2.90 REF			
L2	0.51 BSC			
L3	0.88	-	1.28	
L4	0.50	-	1.00	
L5	1.65	1.80	1.95	
θ	0°	-	8°	



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